

50. A method according to claim 47 in which said optical inspection includes directing a beam of radiation onto said sample to produce detectable radiation which is reflected from and/or transmitted through said sample.

51. A method according to claim 50 in which only detectable radiation which is reflected from said disc is measured.

52. A method according to claim 50 in which detectable radiation which is both reflected from and transmitted through said disc is measured.


53. A method according to claim 50 in which said sample support means is internal to said disc.

REMARKS

The Commissioner is hereby authorized to charge any additional filing fees under 37 C.F.R. § 1.16, or application processing fees under 37 C.F.R. § 1.17, which may be required now or during the pendency of this application, or credit any overpayment to Account No. 16-2230.

Respectfully submitted,

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MARKED UP VERSION OF THE STATEMENT OF RELATED CASES

This Application Is A Divisional Of Copending Application Serial No. [09/643,030] 09/665,930,
Filed [August 21, 2000] September 20, 2000 now United States Letters Patent No. 6,327,031,
Which Is A Continuation Of [Copending] Application Serial No. 09/156,475, Filed September
18, 1998, Now U.S. Patent No. 6,256,088, Which Is A Continuation Of Application Serial No.
08/809,402, Now U.S. Patent No. 5,892,577, Filed July 28, 1997 [Issued On April 6, 1999];
Which Is A 371 Continuation Of PCT/GB95/02186, Filed September 15, 1995, Which Claims
Priority From UK Patent Application No. 9418981.8 Filed September 21, 1994.

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MARKED UP COPY OF THE TITLE

Apparatus and Method for Carrying Out Analysis of Samples Using Semi-Reflective [Detector Split] Beam Radiation Inspection.

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